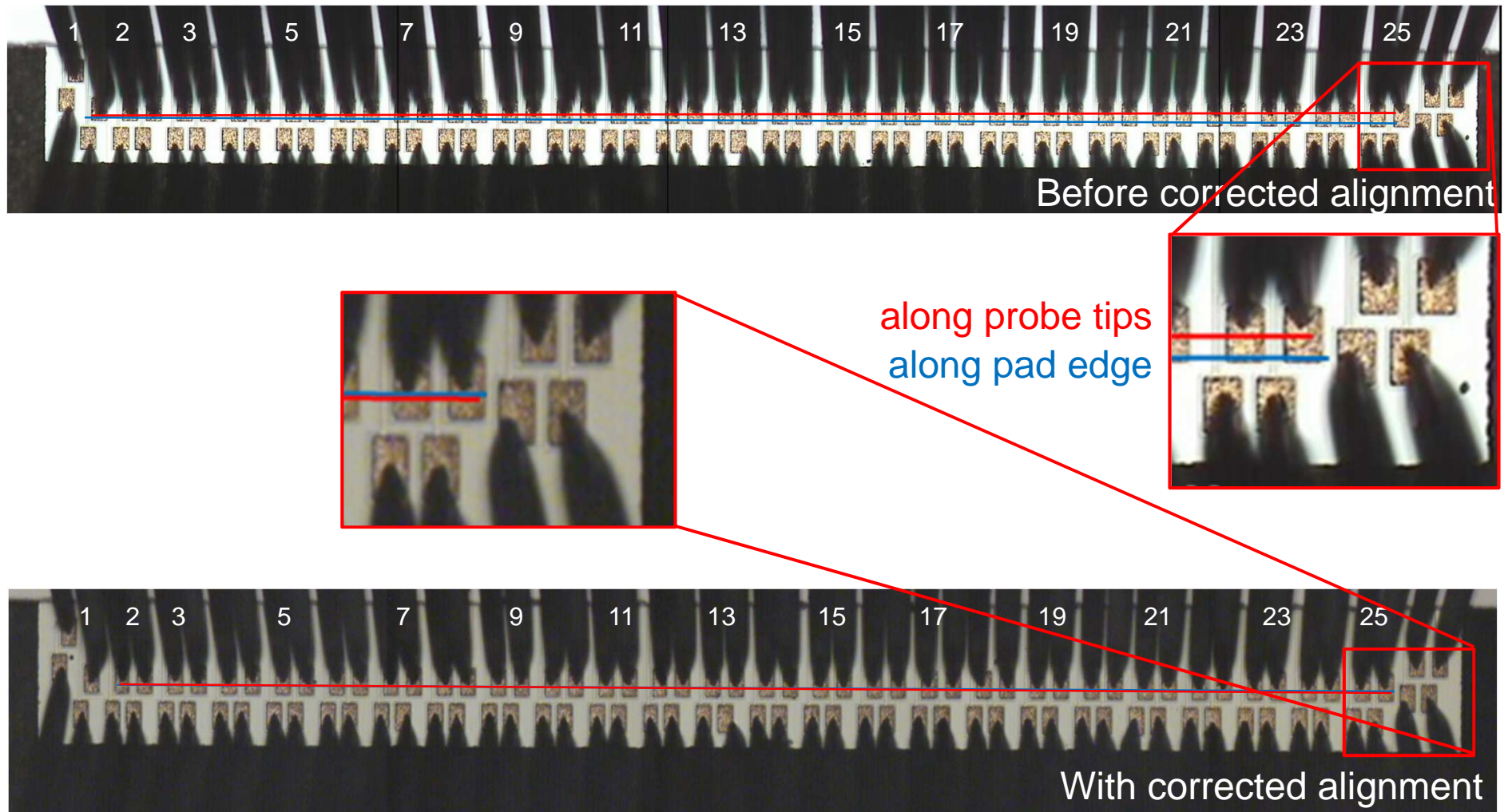


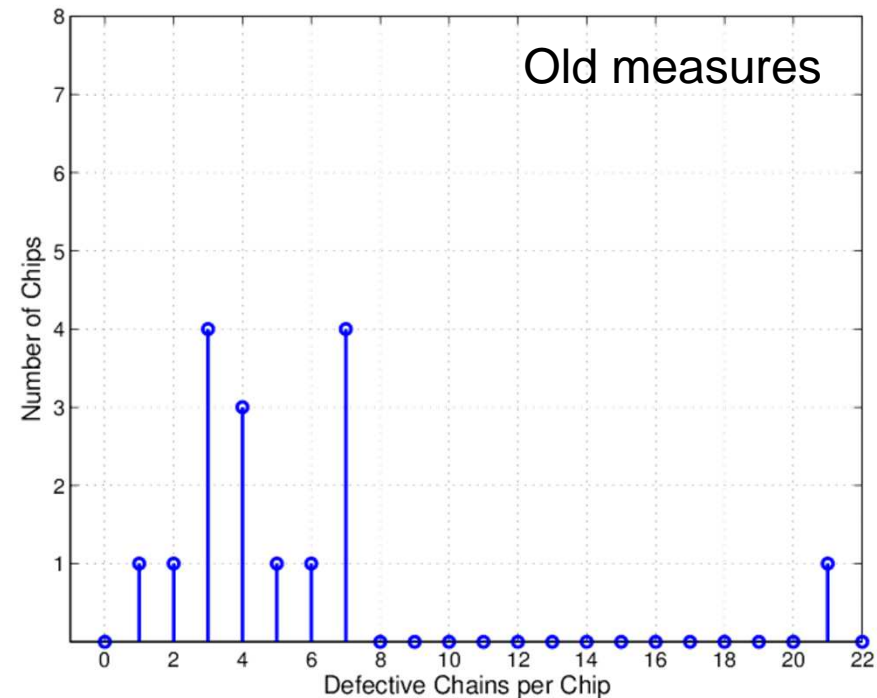
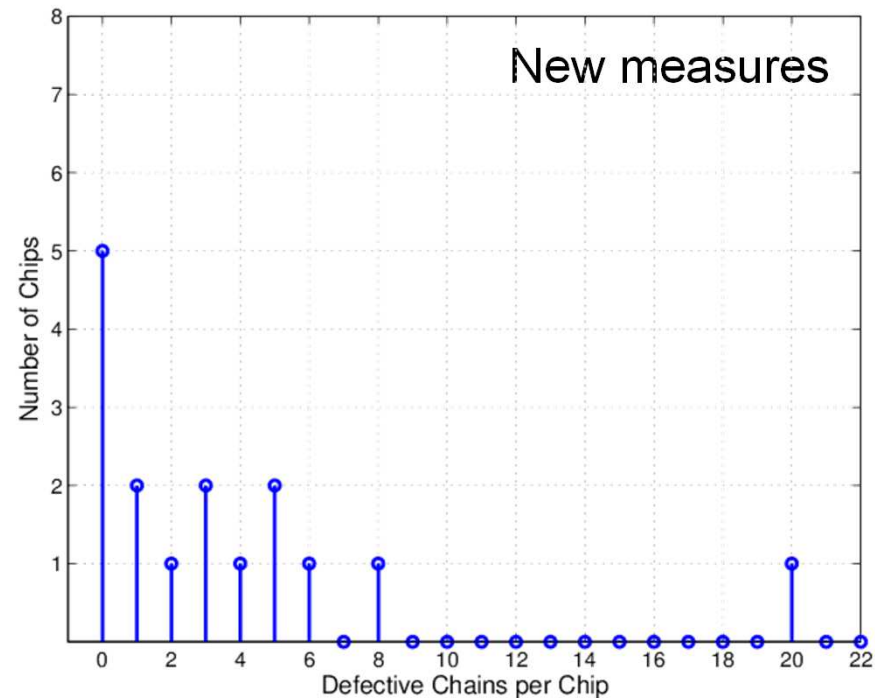
# Probecard misalignment found and corrected

## PICTURES OF PROBE TIPS DURING TESTS



# With improved probecard alignment there are even five chips without defect

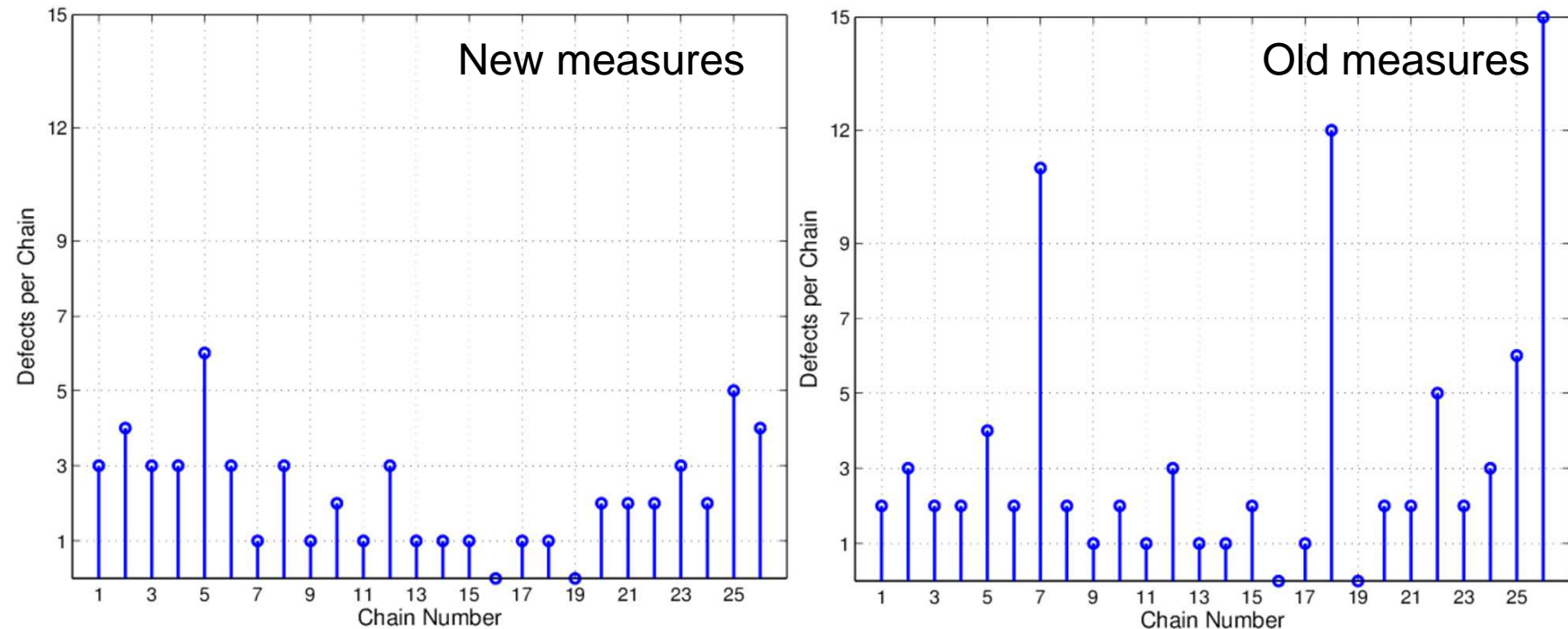
TEST-RESULTS (MODULE 1) WITH ALIGNED PROBECARD,  
DEFECTS PER CHIP



Module 1 only

# With improved probecard alignment the leveling issue is not that obvious

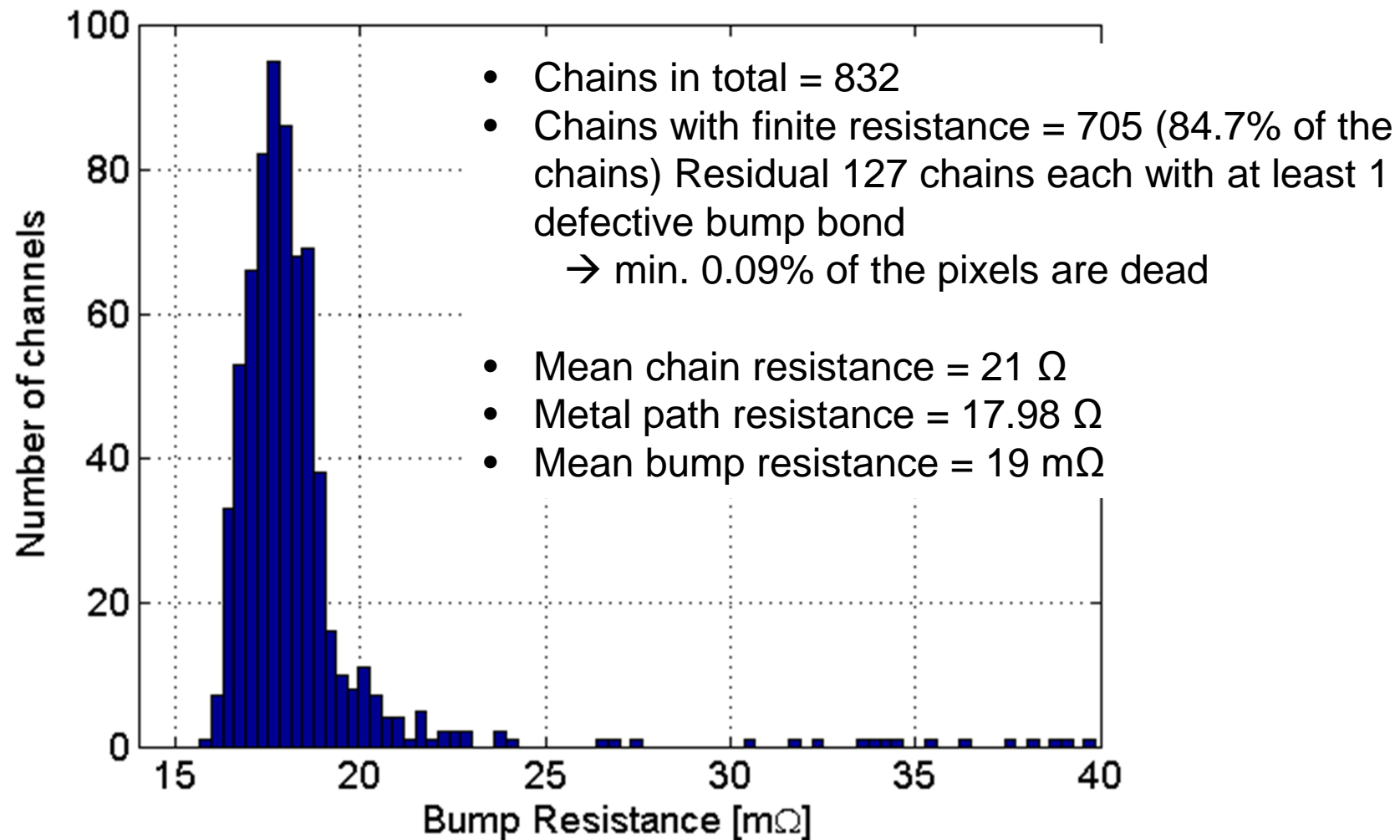
TEST-RESULTS (MODULE 1) WITH ALIGNED PROBECARD,  
DEFECTS PER CHAIN



Module 1 only

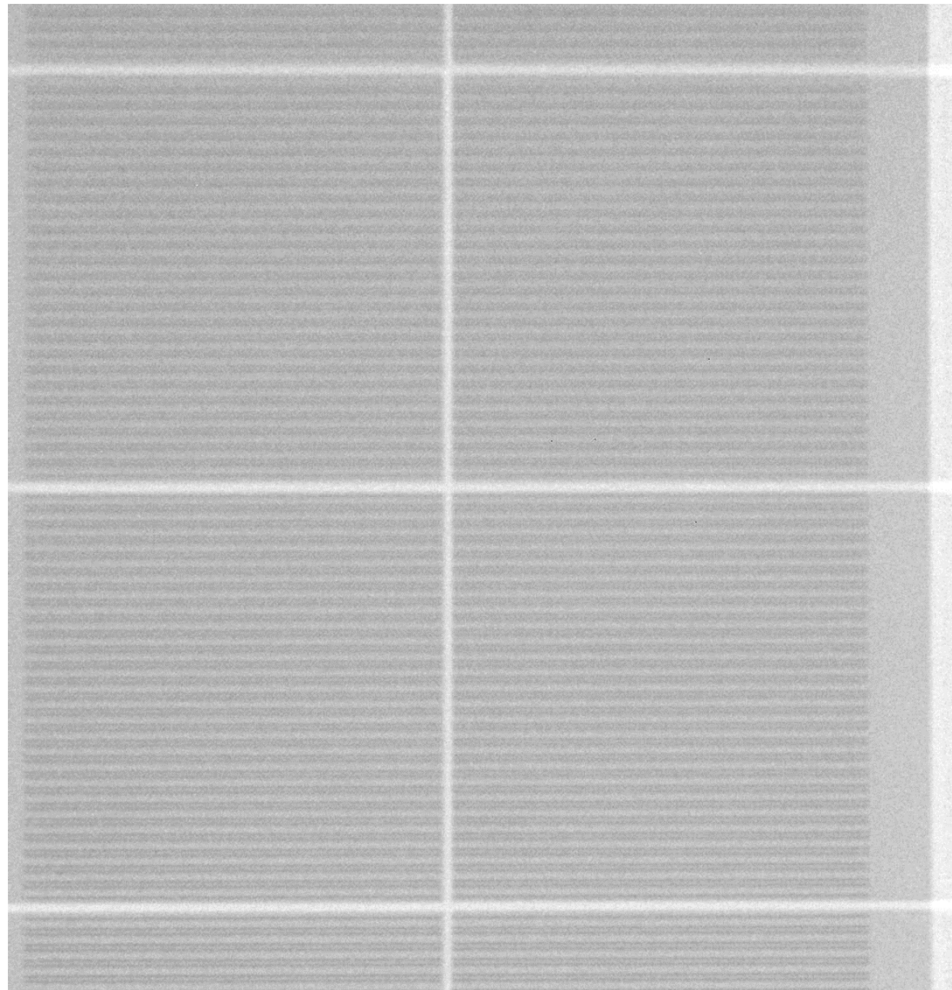
# With improved probecard alignment the result is improved

## TEST-RESULTS (MODULE 1 (IMPROVED) AND 2), HISTOGRAM



# X-ray contrast of the Jülich CT is too low for our samples

## 2D X-RAY IMAGE OF MODULE 2





# X-ray contrast of the Jülich CT is too low for our samples

## 3D X-RAY IMAGES OF MODULE 2

